



DATE: Saturday, November 20, 2004

WEST Search History

Set Name Query

Hit Count

DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ

L17	L14 and index near4 S	2
L16	L14 and index S	1
L15	L14 and l2	1
L14	L13 and l1	508
L13	electrical conductivity	71394
L12	l10 and l1	2
L11	L10 and l7	0
L10	"tau.sup.1/2 "	17
L9	".tau.sup.1/2 "	0
L8	".tau..sup.1/2 "	0
L7	l4 same (semiconductor or wafer or work piece or workpiece) and l1	175
L6	l4 same (semiconductor or wafer or work piece or workpiece) same l1	1
L5	l1 and L4	362
L4	(control or controlling or modify or modifying or modification or alter or change) near5 conductivity	29726
L3	l1 same L2	1
L2	(emission or irradiation) index	122
L1	(J or mJ) "cm.sup.2 "	15645

END OF SEARCH HISTORY

11/20/04 C-20